捷多邦,专业PCB打样**\$N54AB可373**出**\$N**74ABT373 OCTAL TRANSPARENT D-TYPE LATCHES WITH 3-STATE OUTPUTS

SCBS155D - JANUARY 1991 - REVISED MAY 1997

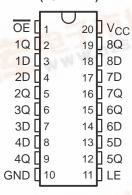
- State-of-the-Art EPIC-IIB™ BiCMOS Design
 Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C
- High-Drive Outputs (-32-mA I_{OH}, 64-mA I_{OL})
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Ceramic Flat (W) Package, and Plastic (N) and Ceramic (J) DIPs

description

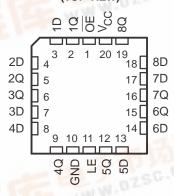
The eight latches of the 'ABT373 are transparent D-type latches. While the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the logic levels set up at the D inputs.

A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without need for interface or pullup components.

SN54ABT373 . . . J OR W PACKAGE SN74ABT373 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54ABT373 ... FK PACKAGE (TOP VIEW)



OE does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT373 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT373 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each latch)

	(
	INPUTS	OUTPUT	
OE	LE	D	Q
. E0	Н	Н	Н
L	Н	L	L
L	L	Χ	Q ₀
Н	X	Χ	Z

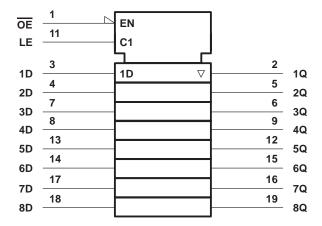
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





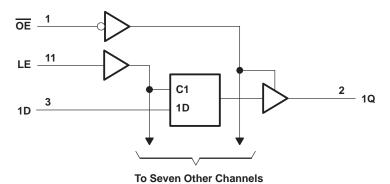
SCBS155D - JANUARY 1991 - REVISED MAY 1997

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1)		-0.5 V to 7 V
Voltage range applied to any output in the high of	or power-off state, VO	\dots –0.5 V to 5.5 V
Current into any output in the low state, IO: SN5	54ABT373	96 mA
SN7	'4ABT373	128 mA
Input clamp current, I _{IK} (V _I < 0)		–18 mA
Output clamp current, I _{OK} (V _O < 0)		–50 mA
Package thermal impedance, θ_{JA} (see Note 2):	DB package	115°C/W
	DW package	97°C/W
	N package	67°C/W
	PW package	128°C/W
Storage temperature range, T _{stq}		65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

^{2.} The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero.



NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

SN54ABT373, SN74ABT373 **OCTAL TRANSPARENT D-TYPE LATCHES** WITH 3-STATE OUTPUTS SCBS155D – JANUARY 1991 – REVISED MAY 1997

recommended operating conditions (see Note 3)

			SN54A	BT373	SN74A	BT373	UNIT
			MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage		4.5	5.5	4.5	5.5	V
VIH High-level input voltage		2		2		V	
V _{IL} Low-level input voltage			0.8		0.8	V	
V _I Input voltage		0	VCC	0	VCC	V	
ІОН	High-level output current			-24		-32 mA	
loL	DL Low-level output current			48		64	mA
Δt/Δν	Input transition rise or fall rate	Outputs enabled		5		5	ns/V
TA	Operating free-air temperature		- 55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		Т	A = 25°C	;	SN54A	BT373	SN74A	UNIT		
PARAMETER		1E21 CONDITION	N3	MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNII
VIK	$V_{CC} = 4.5 V$,	$I_{I} = -18 \text{ mA}$				-1.2		-1.2		-1.2	V
	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$		2.5			2.5		2.5		
\\\\	$V_{CC} = 5 V$,	$I_{OH} = -3 \text{ mA}$		3			3		3		V
VOH	I V C C = 4 5 V F	$I_{OH} = -24 \text{ mA}$		2			2				V
	VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$		2*					2		
VOL	V _{CC} = 4.5 V	$I_{OL} = 48 \text{ mA}$				0.55		0.55			V
VOL	IOL = 64 mA					0.55*				0.55	V
V_{hys}					100						mV
lį	$V_{CC} = 5.5 V$,	$V_I = V_{CC}$ or GND				±1		±1		±1	μΑ
lozh	$V_{CC} = 5.5 V$,	$V_0 = 2.7 \text{ V}$				10‡		10‡		10‡	μΑ
lozL	$V_{CC} = 5.5 \text{ V},$	$V_0 = 0.5 V$				-10‡		-10‡		-10‡	μΑ
l _{off}	$V_{CC} = 0$,	V_I or $V_O \le 4.5 \text{ V}$				±100				±100	μΑ
ICEX	$V_{CC} = 5.5 V$,	V _O = 5.5 V	Outputs high			50		50		50	μΑ
IO§	$V_{CC} = 5.5 \text{ V},$	V _O = 2.5 V		- 50	-100	-180	- 50	-180	-50	-180	mA
	\\\	- 0	Outputs high		1	250		250		250	μΑ
Icc	$V_{CC} = 5.5 \text{ V}, I_{C}$ $V_{I} = V_{CC} \text{ or } G$		Outputs low		24	30		30		30	mA
	1, 100 31 31		Outputs disabled		0.5	250		250		250	μΑ
ΔI _{CC} ¶	V _{CC} = 5.5 V, C Other inputs at	One input at 3.4 V, VCC or GND				1.5		1.5		1.5	mA
Ci	$V_{I} = 2.5 \text{ V or } 0.$.5 V			3						pF
Co	$V_0 = 2.5 \text{ V or } 0$	0.5 V			6						pF

^{*} On products compliant to MIL-PRF-38535, this parameter does not apply.



[†] All typical values are at $V_{CC} = 5 \text{ V}$.

[‡] This data sheet limit may vary among suppliers.

[§] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

[¶] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

SN54ABT373, SN74ABT373 OCTAL TRANSPARENT D-TYPE LATCHES WITH 3-STATE OUTPUTS

SCBS155D - JANUARY 1991 - REVISED MAY 1997

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

					SN54ABT373			
				V _{CC} =	V _{CC} = 5 V, T _A = 25°C MIN		MAX	UNIT
		MIN	MAX					
t _W Pulse duration, LE high			3.3		3.3		ns	
Ţ.	A Color Care data before LE		High	2.2		2.5		ns
t _{su}	Setup time, data before LE↓	etup time, data belore LEV		2.2		2.5		115
t _h	Hold time, data after LE \downarrow		High or low	2.2		2.5		ns

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

				SN74ABT373			
			V _{CC} :	= 5 V, 25°C	MIN	MAX	UNIT
			MIN	MAX			
t _W Pulse duration, LE high			3.3		3.3		ns
	Cation time data hafana I C	High	1.9		1.9		no
t _{su}	Setup time, data before LE↓	Low	1.5		1.5		ns
th	Hold time, data after LE↓	High or low	1		1		ns

SN54ABT373, SN74ABT373 OCTAL TRANSPARENT D-TYPE LATCHES WITH 3-STATE OUTPUTS

SCBS155D - JANUARY 1991 - REVISED MAY 1997

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

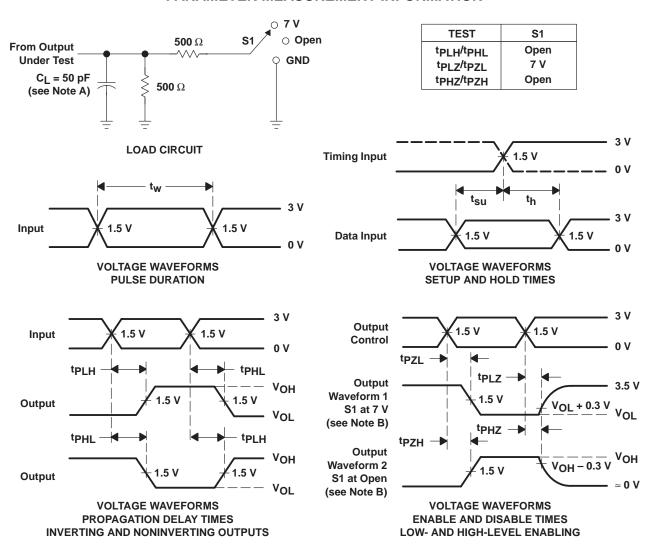
				SN	54ABT3	73		
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V ₍	CC = 5 V A = 25°C	/, ;	MIN	MAX	UNIT
			MIN	TYP	MAX			
^t PLH	D	Q	1.9	3.9	5.4	1.3	6.8	ns
^t PHL		ά	2.2	4.2	5.7	2	7	115
t _{PLH}	LE	Q	2.2	4.6	6.1	1.8	7.7	ns
^t PHL	LL	ά	3.2	5.2	6.7	2.5	7.7	115
^t PZH	ŌĒ	Q	1.2	3.2	5.5	1	6.2	ns
t _{PZL}	OE	ά	2	4.7	6.2	1.5	7.2	115
^t PHZ	ŌĒ	Q	2.5	4.9	6.4	2.4	8	ns
t _{PLZ}	OE .	ζ	2	4.5	6	2	7	115

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

				SN	74ABT3	73		
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V ₍	CC = 5 V A = 25°C	/, ;	MIN	MAX	UNIT
			MIN	TYP	MAX			
t _{PLH}	D	Q	1.9	3.9	5.4	1.9	5.9	ns
t _{PHL}		ų ,	2.2	4.2	5.7	2.2	6.2	115
t _{PLH}	1.5	Q	2.2	4.6	6.1	2.2	6.6	ns
^t PHL	LE	ų ,	3.2	5.2	6.7	3.2	7.2	115
^t PZH		Q	1.2	3.2	4.7	1.2	5.2	20
tPZL	ŌĒ		2.7	4.7	6.2	2.7	6.7	ns
^t PHZ	ŌĒ	Q	2.5	4.9	6.4	2.5	6.9	ns
t _{PLZ}	OE .		2	4.5	6	2	6.5	115

SCBS155D - JANUARY 1991 - REVISED MAY 1997

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated